

## FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 1 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | NAME            | CLASS | SUBCLASS | FILING<br>DATE |
|----------------------|----|--------------------|-------|-----------------|-------|----------|----------------|
| TW                   | AA | 3,953,566          | 04/76 | Gore            |       |          |                |
|                      | AB | 3,962,653          | 06/76 | Basset          |       |          |                |
|                      | AC | 4,187,390          | 02/80 | Gore            |       |          |                |
|                      | AD | 4,482,516          | 11/84 | Bowman et al    |       |          |                |
|                      | AE | 4,579,772          | 04/86 | Bhatt et al     |       |          |                |
|                      | AF | 4,642,160          | 02/87 | Burgess         |       |          |                |
|                      | AG | 4,675,789          | 06/87 | Kuwabara et al  |       |          |                |
|                      | AH | 4,713,137          | 12/87 | Sexton          |       |          |                |
|                      | AI | 4,783,345          | 11/88 | Kleeberg et al  |       |          |                |
|                      | AJ | 4,864,722          | 09/89 | Lazzarini et al |       |          |                |
|                      | AK | 5,129,142          | 07/92 | Bindra et al    |       |          |                |
| TW                   | AL | 5,229,550          | 07/93 | Bindra et al    |       |          |                |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION |
|----------------------|----|--------------------|------|---------|-------|----------|-------------|
|                      | AM |                    |      |         |       |          |             |
|                      | AN |                    |      |         |       |          |             |
|                      | AO |                    |      |         |       |          |             |
|                      | AP |                    |      |         |       |          |             |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

10/29/05

FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 2 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | NAME               | CLASS | SUBCLASS | FILING<br>DATE |
|----------------------|----|--------------------|-------|--------------------|-------|----------|----------------|
| <i>TM</i>            | AA | 5,246,817          | 09/93 | Shipley            |       |          |                |
|                      | AB | 5,368,921          | 11/94 | Ishii et al        |       |          |                |
|                      | AC | 5,376,453          | 12/94 | von Gentzkow et al |       |          |                |
|                      | AD | 5,418,689          | 05/95 | Alpaugh et al      |       |          |                |
|                      | AE | 5,483,101          | 01/96 | Shimoto et al      |       |          |                |
|                      | AF | 5,565,267          | 10/96 | Capote et al       |       |          |                |
|                      | AG | 5,648,171          | 07/97 | von Gentzkow et al |       |          |                |
|                      | AH | 5,652,055          | 07/97 | King et al         |       |          |                |
|                      | AI | 5,670,262          | 09/97 | Dalman             |       |          |                |
|                      | AJ | 5,677,045          | 10/97 | Nagai et al        |       |          |                |
|                      | AK | 5,685,070          | 11/97 | Alpaugh et al      |       |          |                |
| <i>TM</i>            | AL | 5,726,863          | 03/88 | Nakayama et al     |       |          |                |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION |
|----------------------|----|--------------------|------|---------|-------|----------|-------------|
|                      | AM |                    |      |         |       |          |             |
|                      | AN |                    |      |         |       |          |             |
|                      | AO |                    |      |         |       |          |             |
|                      | AP |                    |      |         |       |          |             |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

10/29/05

## FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 3 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | NAME          | CLASS | SUBCLASS | FILING<br>DATE |
|----------------------|----|--------------------|-------|---------------|-------|----------|----------------|
| TW                   | AA | 5,814,405          | 09/98 | Branca et al  |       |          |                |
|                      | AB | 5,981,880          | 11/99 | Appelt et al  |       |          |                |
|                      | AC | 6,018,196          | 01/00 | Noddin        |       |          |                |
|                      | AD | 6,042,685          | 03/00 | Shinada et al |       |          |                |
|                      | AE | 6,119,338          | 09/00 | Wang et al    |       |          |                |
|                      | AF | 6,143,401          | 11/00 | Fischer       |       |          |                |
|                      | AG | 6,207,595 B1       | 03/01 | Appelt et al  |       |          |                |
|                      | AH | 6,212,769 B1       | 04/01 | Boyko et al   |       |          |                |
|                      | AI | 6,248,959 B1       | 06/01 | Sylvester     |       |          |                |
|                      | AJ | 6,291,779 B1       | 09/01 | Lubert et al  |       |          |                |
|                      | AK | 6,323,436 B1       | 11/01 | Hedrick et al |       |          |                |
|                      | AL | 6,378,201 B1       | 04/02 | Tsukada et al |       |          |                |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION |
|----------------------|----|--------------------|------|---------|-------|----------|-------------|
|                      | AM |                    |      |         |       |          |             |
|                      | AN |                    |      |         |       |          |             |
|                      | AO |                    |      |         |       |          |             |
|                      | AP |                    |      |         |       |          |             |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

10/29/05

## FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 4 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | NAME          | CLASS | SUBCLASS | FILI<br>NG |
|----------------------|----|--------------------|-------|---------------|-------|----------|------------|
| TJW                  | AA | 6,405,431 B1       | 06/02 | Shin et al    |       |          |            |
|                      | AB | 6,506,979 B1       | 01/03 | Shelnut et al |       |          |            |
|                      | AC | 6,541,589 B1       | 04/03 | Baillie       |       |          |            |
|                      | AD | 6,586,687 B2       | 07/03 | Lee et al     |       |          |            |
|                      | AE | US2002/0150673     | 10/02 | Thorn et al   |       |          |            |
|                      | AF | US2002/0170827     | 11/02 | Furuya        |       |          |            |
|                      | AG | US2002/0172019     | 11/02 | Suzuki et al  |       |          |            |
|                      | AH | US2002/0190378     | 12/02 | Hus et al     |       |          |            |
| TJW                  | AI | US2003/0022013     | 01/03 | Japp et al    |       |          |            |
|                      | AJ |                    |       |               |       |          |            |
|                      | AK |                    |       |               |       |          |            |
|                      | AL |                    |       |               |       |          |            |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | COUNTRY | CLASS | SUBCLASS | TRANSLATION |
|----------------------|----|--------------------|-------|---------|-------|----------|-------------|
| TJW                  | AM | JP 56049271        | 05/81 | Japan   |       |          | Abstract    |
| I                    | AN | JP 7086710         | 03/95 | Japan   |       |          | Abstract    |
|                      | AO | JP 7097466         | 04/95 | Japan   |       |          | Abstract    |
| TJW                  | AP | JP 8092394         | 04/96 | Japan   |       |          | Abstract    |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

10/29/05

## FORM PTO 1449 (Modified)

LIST OF PATENTS AND  
PUBLICATIONS FOR  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENTPage 5 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

## U. S. PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE | NAME | CLASS | SUBCLASS | FILI<br>NG |
|----------------------|----|--------------------|------|------|-------|----------|------------|
|                      | AA |                    |      |      |       |          |            |
|                      | AB |                    |      |      |       |          |            |
|                      | AC |                    |      |      |       |          |            |
|                      | AD |                    |      |      |       |          |            |
|                      | AE |                    |      |      |       |          |            |
|                      | AF |                    |      |      |       |          |            |
|                      | AG |                    |      |      |       |          |            |
|                      | AH |                    |      |      |       |          |            |
|                      | AI |                    |      |      |       |          |            |
|                      | AJ |                    |      |      |       |          |            |
|                      | AK |                    |      |      |       |          |            |
|                      | AL |                    |      |      |       |          |            |

## FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIALS |    | DOCUMENT<br>NUMBER | DATE  | COUNTRY | CLASS | SUBCLASS | TRANSLAT |
|----------------------|----|--------------------|-------|---------|-------|----------|----------|
| TW                   | AM | JP2001015912A2     | 01/01 | Japan   |       |          | Abstract |
| TW                   | AN | JP2002223070A2     | 08/02 | Japan   |       |          | Abstract |
|                      | AO |                    |       |         |       |          |          |
|                      | AP |                    |       |         |       |          |          |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

10/20/2005